AFM Probe Specifications:
Coating
Electrically Conductive
Additional Info
The 240AC-PP AFM probes are designed for tapping mode electrical characterization measurements such as Electrostatic Force Microscopy (EFM), Kelvin Probe Force Microscopy (KPFM), etc.
The tetrahedral AFM tip is located precisely at the free end of the AFM cantilever. This allows the AFM tip to be positioned accurately over the area of interest on the sample surface.
The overall platinum coating ensures high electrical conductivity and significantly enhances the AFM cantilever reflectivity.

AFM Tip:

Shape	Height	Setback	Radius	Half Cone Angle
Optimized Positioning	14 µm (12 - 16 µm)*	0 µm	< 25 nm	0° front, 35° back, <9° side

* typical values

AFM Cantilever:

Cantilever	Shape	Force Const.	Res. Freq.	Lenght	Width	Thickness
Soft tapping mode AFM cantilever	Beam	2 N/m (0.6 - 3.9 N/m)*	70 kHz (45 - 90 kHz)*	240 µm (1 - 250µm)*	40 µm (38 - 42µm)*	2.6µm (2.1 - 3.1 µm)*

* typical values